

100360



T-45-17

# 100360 Low Power Dual Parity Checker/Generator

## General Description

The 100360 is a dual parity checker/generator. Each half has nine inputs; the output is HIGH when an even number of inputs are HIGH. One of the nine inputs ( $I_a$  or  $I_b$ ) has the shorter through-put delay and is therefore preferred as the expansion input for generating parity for 16 or more bits.

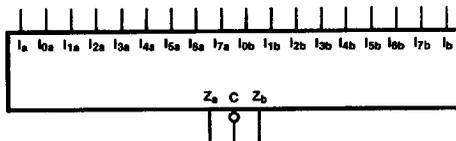
The 100360 also has a Compare ( $\bar{C}$ ) output which allows the circuit to compare two 8-bit words. The  $\bar{C}$  output is LOW when the two words match, bit for bit. All inputs have 50 k $\Omega$  pulldown resistors.

## Features

- Lower power than 100160
- 2000V ESD protection
- Pin/function compatible with 100160
- Voltage compensated operating range = -4.2V to -5.7V
- Min to Max propagation delay 35% tighter than 100160
- Available to industrial grade temperature range

**Ordering Code:** See Section 6

## Logic Symbol

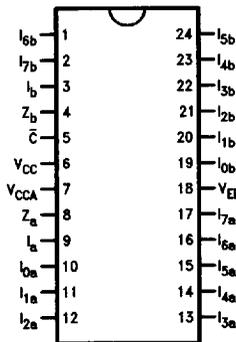


Pin Names	Description
$I_a, I_b, I_{1a}, I_{1b}$	Data Inputs
$Z_a, Z_b$	Parity Odd Outputs
$\bar{C}$	Compare Output

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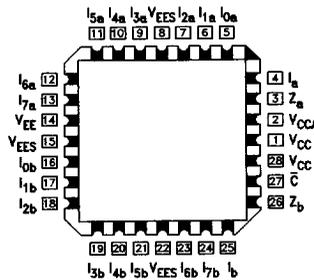
## Connection Diagrams

24-Pin DIP



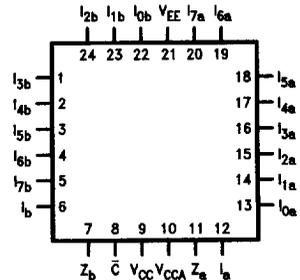
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28-Pin PCC



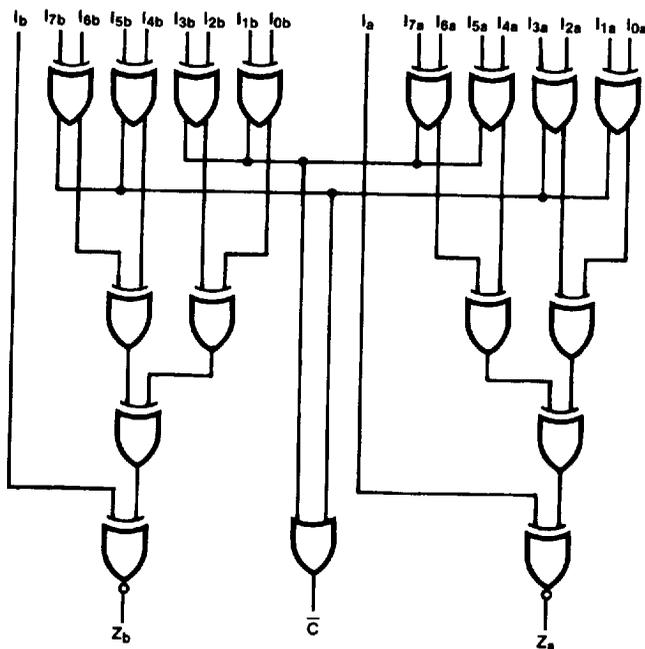
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24-Pin Quad Cerpak



TL/F/10611-3

**Logic Diagram**



TL/F/10611-5

**Truth Table (Each Half)**

Sum of HIGH Inputs	Output Z
Even	HIGH
Odd	LOW

**Comparator Function**

$$\bar{C} = (I_{0a} \oplus I_{1a}) + (I_{2a} \oplus I_{3a}) + (I_{4a} \oplus I_{5a}) + (I_{6a} \oplus I_{7a}) + (I_{0b} \oplus I_{1b}) + (I_{2b} \oplus I_{3b}) + (I_{4b} \oplus I_{5b}) + (I_{6b} \oplus I_{7b})$$

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### Absolute Maximum Ratings

Above which the useful life may be impaired (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature (T<sub>STG</sub>) -65°C to +150°C

Maximum Junction Temperature (T<sub>J</sub>)

Ceramic +175°C

Plastic +150°C

V<sub>EE</sub> Pin Potential to Ground Pin -7.0V to +0.5V

Input Voltage (DC) V<sub>EE</sub> to +0.5V

Output Current (DC Output HIGH) -50 mA

ESD (Note 2) ≥2000V

**Note 1:** Absolute maximum ratings are those values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** ESD testing conforms to MIL-STD-883, Method 3015.

### Recommended Operating Conditions

Case Temperature (T<sub>C</sub>)

Commercial

0°C to +85°C

Industrial

-40°C to +85°C

Military

-55°C to +125°C

Supply Voltage (V<sub>EE</sub>)

-5.7V to -4.2V

### Commercial Version

### DC Electrical Characteristics

V<sub>EE</sub> = -4.2V to -5.7V, V<sub>CC</sub> = V<sub>CCA</sub> = GND, T<sub>C</sub> = 0°C to +85°C (Note 3)

Symbol	Parameter	Min	Typ	Max	Units	Conditions	
						V <sub>IN</sub> = V <sub>IH</sub> (Max) or V <sub>IL</sub> (Min)	Loading with 50Ω to -2.0V
V <sub>OH</sub>	Output HIGH Voltage	-1025	-955	-870	mV	V <sub>IN</sub> = V <sub>IH</sub> (Max) or V <sub>IL</sub> (Min)	Loading with 50Ω to -2.0V
V <sub>OL</sub>	Output LOW Voltage	-1830	-1705	-1620	mV		
V <sub>OHC</sub>	Output HIGH Voltage	-1035			mV	V <sub>IN</sub> = V <sub>IH</sub> (Min) or V <sub>IL</sub> (Max)	Loading with 50Ω to -2.0V
V <sub>OLC</sub>	Output LOW Voltage			-1610	mV		
V <sub>IH</sub>	Input HIGH Voltage	-1165		-870	mV	Guaranteed HIGH Signal for All Inputs	
V <sub>IL</sub>	Input LOW Voltage	-1830		-1475	mV	Guaranteed LOW Signal for All Inputs	
I <sub>IL</sub>	Input LOW Current	0.50			μA	V <sub>IN</sub> = V <sub>IL</sub> (Min)	
I <sub>IH</sub>	Input HIGH Current I <sub>a</sub> , I <sub>b</sub> I <sub>na</sub> , I <sub>nb</sub>			340 240	μA	V <sub>IN</sub> = V <sub>IH</sub> (Max)	
I <sub>EE</sub>	Power Supply Current	-100		-50	mA	Inputs Open	

**Note 3:** The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions.

### DIP AC Electrical Characteristics

V<sub>EE</sub> = -4.2V to -5.7V, V<sub>CC</sub> = V<sub>CCA</sub> = GND

Symbol	Parameter	T <sub>C</sub> = 0°C		T <sub>C</sub> = +25°C		T <sub>C</sub> = +85°C		Units	Conditions
		Min	Max	Min	Max	Min	Max		
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay I <sub>na</sub> , I <sub>nb</sub> to Z <sub>a</sub> , Z <sub>b</sub>	1.10	2.75	1.10	2.75	1.10	2.75	ns	Figures 1 & 2
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay I <sub>na</sub> , I <sub>nb</sub> to $\bar{C}$	1.10	2.80	1.10	2.80	1.10	2.80	ns	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay I <sub>a</sub> , I <sub>b</sub> to Z <sub>a</sub> , Z <sub>b</sub>	0.50	1.20	0.60	1.30	0.60	1.30	ns	
t <sub>TLH</sub> t <sub>THL</sub>	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	

**Commercial Version** (Continued)

**PCC and Cerpak AC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = 0^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $Z_a, Z_b$	1.10	2.75	1.10	2.75	1.10	2.75	ns	Figures 1 & 2
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $\bar{C}$	1.10	2.80	1.10	2.80	1.10	2.80	ns	
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_a, I_b$ to $Z_a, Z_b$	0.50	1.20	0.60	1.30	0.60	1.30	ns	
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	

**Industrial Version**

**PCC DC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = -40^\circ C$  to  $+85^\circ C$  (Note 1)

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = 0^\circ C$ to $+85^\circ C$		Units	Conditions	
		Min	Max	Min	Max			
$V_{OH}$	Output HIGH Voltage	-1085	-870	-1025	-870	mV	$V_{IN} = V_{IH}$ (Max) or $V_{IL}$ (Min)	Loading with 50Ω to -2.0V
$V_{OL}$	Output LOW Voltage	-1830	-1575	-1830	-1620	mV		
$V_{OHC}$	Output HIGH Voltage	-1095		-1035		mV	$V_{IN} = V_{IH}$ (Min) or $V_{IL}$ (Max)	Loading with 50Ω to -2.0V
$V_{OLC}$	Output LOW Voltage		-1565		-1610	mV		
$V_{IH}$	Input HIGH Voltage	-1170	-870	-1165	-870	mV	Guaranteed HIGH Signal for All Inputs	
$V_{IL}$	Input LOW Voltage	-1830	-1480	-1830	-1475	mV	Guaranteed LOW Signal for All Inputs	
$I_{IL}$	Input LOW Current	0.50		0.50		μA	$V_{IN} = V_{IL}$ (Min)	
$I_{IH}$	Input HIGH Current $I_a, I_b$ $I_{na}, I_{nb}$		340 240		340 240	μA	$V_{IN} = V_{IH}$ (Max)	
$I_{EE}$	Power Supply Current	-100	-50	-100	-50	mA	Inputs Open	

**Note 1:** The specified limits represent the "worst case" value for the parameter. Since these values normally occur at the temperature extremes, additional noise immunity and guardbanding can be achieved by decreasing the allowable system operating ranges. Conditions for testing shown in the tables are chosen to guarantee operation under "worst case" conditions

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**Industrial Version (Continued)**

**PCC AC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -40^\circ C$		$T_C = +25^\circ C$		$T_C = +85^\circ C$		Units	Conditions
		Min	Max	Min	Max	Min	Max		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $Z_a, Z_b$	1.00	2.75	1.10	2.75	1.10	2.75	ns	Figures 1 & 2
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to C	1.00	2.80	1.10	2.80	1.10	2.80	ns	
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_a, I_b$ to $Z_a, Z_b$	0.50	1.20	0.60	1.30	0.60	1.30	ns	
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns	

**Military Version — Preliminary**

**DC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$ ,  $T_C = -55^\circ C$  to  $+125^\circ C$

Symbol	Parameter	Min	Max	Units	$T_C$	Conditions	Notes	
$V_{OH}$	Output HIGH Voltage	-1025	-870	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH} (Max)$ or $V_{IL} (Min)$	Loading with $50\Omega$ to $-2.0V$	1, 2, 3
		-1085	-870	mV	$-55^\circ C$			
$V_{OL}$	Output LOW Voltage	-1830	-1620	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$	Loading with $50\Omega$ to $-2.0V$	1, 2, 3
		-1830	-1555	mV	$-55^\circ C$			
$V_{OHC}$	Output HIGH Voltage	-1035		mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$	Loading with $50\Omega$ to $-2.0V$	1, 2, 3
		-1085		mV	$-55^\circ C$			
$V_{OLC}$	Output LOW Voltage		-1610	mV	$0^\circ C$ to $+125^\circ C$	$V_{IN} = V_{IH} (Min)$ or $V_{IL} (Max)$	Loading with $50\Omega$ to $-2.0V$	1, 2, 3
			-1555	mV	$-55^\circ C$			
$V_{IH}$	Input HIGH Voltage	-1165	-870	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed HIGH Signal for All Inputs	1, 2, 3, 4	
$V_{IL}$	Input LOW Voltage	-1830	-1475	mV	$-55^\circ C$ to $+125^\circ C$	Guaranteed LOW Signal for All Inputs	1, 2, 3, 4	
$I_{IL}$	Input LOW Current	0.50		$\mu A$	$-55^\circ C$ to $+125^\circ C$	$V_{EE} = -4.2V$ $V_{IN} = V_{IL} (Min)$	1, 2, 3	
$I_{IH}$	Input HIGH Current $I_a, I_b$ $I_{na}, I_{nb}$		340 240	$\mu A$	$0^\circ C$ to $+125^\circ C$	$V_{EE} = -5.7V$ $V_{IN} = V_{IH} (Max)$	1, 2, 3	
			490 340	$\mu A$	$-55^\circ C$			
$I_{EE}$	Power Supply Current	-110	-50	mA	$-55^\circ C$ to $+125^\circ C$	Inputs Open	1, 2, 3	

**Note 1:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^\circ C$ ), then testing immediately without allowing for the junction temperature to stabilize due to heat dissipation after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

**Note 2:** Screen tested 100% on each device at  $-55^\circ C$ ,  $+25^\circ C$ , and  $+125^\circ C$ , Subgroups 1, 2, 3, 7, and 8.

**Note 3:** Sample tested (Method 5005, Table I) on each manufactured lot at  $-55^\circ C$ ,  $+25^\circ C$ , and  $+125^\circ C$ , Subgroups A1, 2, 3, 7, and 8.

**Note 4:** Guaranteed by applying specified input condition and testing  $V_{OH}/V_{OL}$ .

**Military Version — Preliminary** (Continued)

**AC Electrical Characteristics**

$V_{EE} = -4.2V$  to  $-5.7V$ ,  $V_{CC} = V_{CCA} = GND$

Symbol	Parameter	$T_C = -55^\circ C$		$T_C = +25^\circ C$		$T_C = +125^\circ C$		Units	Conditions	Notes
		Min	Max	Min	Max	Min	Max			
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $Z_a, Z_b$	1.00	2.95	1.00	2.95	1.00	2.95	ns	Figures 1 & 2	1, 2, 3
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_{na}, I_{nb}$ to $\bar{C}$	1.00	3.00	1.00	3.00	1.00	3.00	ns		
$t_{PLH}$ $t_{PHL}$	Propagation Delay $I_a, I_b$ to $Z_a, Z_b$	0.40	1.40	0.50	1.50	0.50	1.50	ns		
$t_{TLH}$ $t_{THL}$	Transition Time 20% to 80%, 80% to 20%	0.35	1.10	0.35	1.10	0.35	1.10	ns		4

**Note 1:** F100K 300 Series cold temperature testing is performed by temperature soaking (to guarantee junction temperature equals  $-55^\circ C$ ), then testing immediately after power-up. This provides "cold start" specs which can be considered a worst case condition at cold temperatures.

**Note 2:** Screen tested 100% on each device at  $+25^\circ C$  temperature only, Subgroup A9.

**Note 3:** Sample tested (Method 5005, Table I) on each mfg lot at  $+25^\circ C$ , Subgroup A9, and at  $+125^\circ C$  and  $-55^\circ C$  temperatures, Subgroups A10 and A11.

**Note 4:** Not tested at  $+25^\circ C$ ,  $+125^\circ C$ , and  $-55^\circ C$  temperature (design characterization data).

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### Test Circuitry

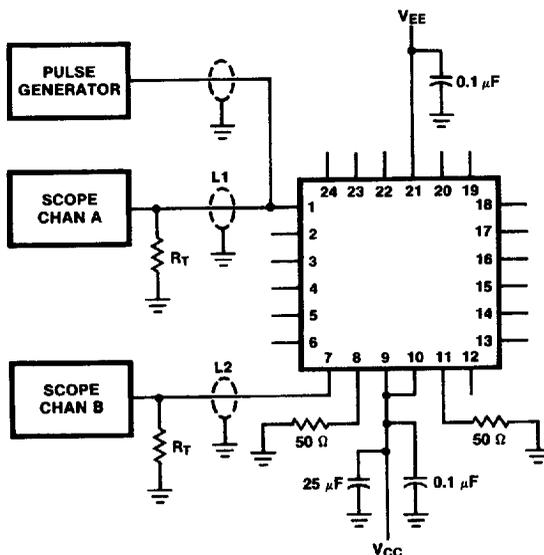


FIGURE 1. AC Test Circuit

TL/F/10611-6

**Notes:**

- V<sub>CC</sub>, V<sub>CCA</sub> = +2V, V<sub>EE</sub> = -2.5V
- L1 and L2 = equal length 50Ω impedance lines
- R<sub>T</sub> = 50Ω terminator internal to scope
- Decoupling 0.1 μF from GND to V<sub>CC</sub> and V<sub>EE</sub>
- All unused outputs are loaded with 50Ω to GND
- C<sub>L</sub> = Fixture and stray capacitance ≤ 3 pF
- Pin numbers shown are for flatpak; for DIP see logic symbol

### Switching Waveforms

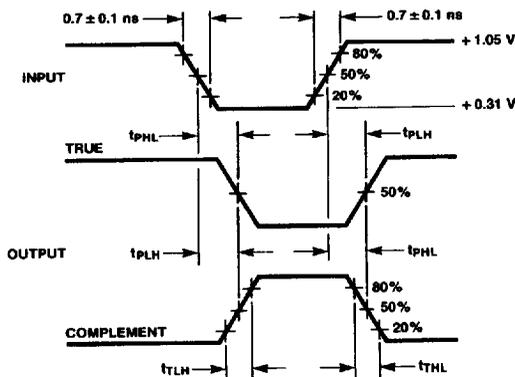


FIGURE 2. Propagation Delay and Transition Times

TL/F/10611-7